

Paper List

January –December, 2026

- [E2026-1\(C\)](#) Statistical Capacitance Measurement of Si Trench Capacitors Using 3D Stacked Array Test Circuit
IEEE 38th International Conference on Microelectronic Test Structures, (ICMTS2026), pp.7-11, March 23-26, (2026) , Matsue, Japan
Ryoya Nishimaki, Koga Saito, Takezo Mawaki, Rihito Kuroda
- [E2026-2\(C\)](#) A 72-dB SNR 1K-fps global shutter CMOS image sensor with dual pixel reset voltage and programmable gain amplifier
Society for Imaging Science and Technology,
Vol.38,ISS-288,pp.288-1-288-7,March, Electronic Imaging (2026), San Francisco, US
Kota Ogino, Takezo Mawaki, Rufuto Koba, Ken Miyauchi, Yushi Sakai, Rihito Kuroda
DOI: [10.2352/EI.2026.38.6.ISS-288](https://doi.org/10.2352/EI.2026.38.6.ISS-288)
- [E2026-3\(C\)](#) A Global Shutter Proximity Capacitance CMOS Image Sensor for High-precision and High-speed Capacitance Imaging
Society for Imaging Science and Technology,
Vol.38,ISS-289,pp.289-1-289-6,March, Electronic Imaging (2026), San Francisco, US
Hiroto Ogura, Ukyo Kotake, Takezo Mawaki, Ken Miyauchi, Rihito Kuroda
DOI: [10.2352/EI.2026.38.6.ISS-289](https://doi.org/10.2352/EI.2026.38.6.ISS-289)
- [E2026-4\(C\)](#) [Invited Paper]
Beyond Image Quality: Violet-Light-Enabled Displays for Visual Health
Society for Information Display International Symposium DISPLAY WEEK,
pp.902-905,65-1, May 7th (2026), Los Angeles, US
Kazuo Tsubota, Takahiro Ishinabe, Yasuyuki Shirai, Koichi Kajiyama, Keisuke Mitsuoka